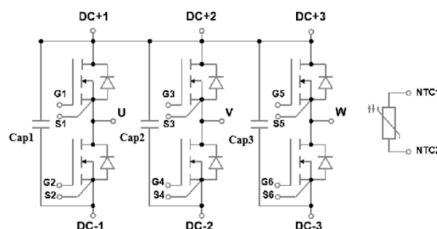
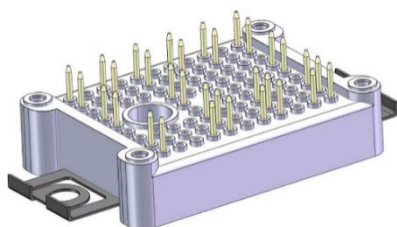


Product Summary

Product Type	V _{DS}	I _D	R _{DS(ON)}	Package
ATSCM40RN120FB EY1B	1200V	80A	40mΩ	EASY-1B



Features

- Optimized 1200V high performance and cost effective SiC technology
- Built-in NTC thermistor for temperature monitoring
- High voltage decoupling capacitors for noise immunity
- Lead free, RoHS compliant
- Ultra-Low Loss
- High Frequency Operation
- Al₂O₃ substrate for reinforced thermal management
- Enhanced electrical isolation and creepage

Applications

- EV Chargers
- Solar
- High-Efficiency Converters / Inverters
- Motor & Traction Drives
- Smart-Grid / Grid-Tied Distributed Generation

Maximum Ratings

Absolute Maximum Ratings (Per Position), T_J=25°C, unless otherwise Specified

Parameter	Symbol	Conditions	Value	Unit
Drain-source voltage	V _{DS}	V _{GS} =0V, I _D = 100μA	1200	V
Gate-source voltage	V _{GSmax}	DC	-8 to 22	V
Gate-source voltage	V _{GS-operation}	DC	-4 to 18	V
Continuous drain current	I _D	T _C =25°C	80	A
		T _C =100°C	56	A
Pulsed drain current	I _{DM}	t _P limited by T _{Jmax}	120	A
Maximum junction temperature	T _{J.max}		150	°C
Operating and storage temperature	T _J ,T _{STG}		-40~125	°C

Thermal Characteristics (Per Position)

Parameter	Symbol	Min	Typ	Max	Unit
thermal resistance, junction-case	R _{thJC}		0.4		K/W
thermal resistance, junction-heatsink	R _{thJH}		1.2		K/W

Not*:Kpaste=3w/mK, Thickness=100um

Static Characteristics (Per Position)

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Drain-source breakdown voltage	BV_{DS}	$V_{GS}=0V, I_D=100\mu A$	1200			V
Total drain leakage current	I_{DSS}	$V_{DS}=1200V, V_{GS}=0V, T_J=25^\circ$		1	10	μA
Total gate leakage current	I_{GSS}	$V_{DS}=0V, T_J=25^\circ C, V_{GS}=15V$			100	nA
Drain-source on resistance	$R_{DS(on)}$	$V_{GS}=15V, I_D=33.3A, T_J=25^\circ$		40	50	m Ω
		$V_{GS}=15V, I_D=33.3A, T_J=150^\circ$		57		
		$V_{GS}=18V, I_D=33.3A, T_J=25^\circ$		32	40	
		$V_{GS}=18V, I_D=33.3A, T_J=150^\circ$		55		
Gate threshold voltage	$V_{G(th)}$	$V_{DS}=V_{GS}, I_D=10mA, T_J=25^\circ$	2.3	2.8	3.6	V
		$V_{DS}=V_{GS}, I_D=10mA, T_J=150^\circ$		2.2		
Gate resistance	R_G	$f=1MHz, V_{AC}=25mV$		0.9		Ω
Diode forward voltage	V_{SD}	$V_{GS}=-4V, I_{SD}=20A, T_J=25^\circ$		3.8		V
		$V_{GS}=-4V, I_{SD}=20A, T_J=150^\circ$		3.5		
Continuous diode forward current	I_S	$V_{GS}=-4V, T_C=25^\circ$		76		A

Typical Performance -Dynamic

Parameter	Symbol	Test condition	Min	Typ	Max	Unit
Input capacitance	C_{iss}	$V_{DS}=1000V, V_{GS}=0V$ $V_{AC}=25mV,$ $f=100kHz$		2159		pF
Output capacitance	C_{oss}			127		
Reverse transfer capacitance	C_{rss}			10		
Coss stored energy	E_{oss}			79		μJ
Total gate charge	Q_G	$V_{DS}=800V, I_D=40A,$ $V_{GS}=-4V \text{ to } +15V$		76		nC
Gate-source charge	Q_{GD}			36		nC
Gate-drain charge	Q_{GS}			16		nC
Turn-on delay time	$t_{d(on)}$	$V_{DS}=800V, I_D=40A,$ Gate Driver = -4V to +15V, $R_G=2.5\Omega,$ $L=120\mu H$		31		ns
Rise time	t_r			18		ns
Turn-off delay time	$t_{d(off)}$			32		ns
Fall time	t_f			9		ns
Turn on energy	E_{on}			259		μJ
Turn off energy	E_{off}			50		μJ
Reverse recovery time	t_{rr}	$V_R=800V, V_{GS}=-4V$ $I_D=40A; di/dt=2281A/\mu S$ $T_J=150^\circ C$		55		ns
Reverse recovery charge	Q_{rr}			750		nC
Peak reverse recovery current	I_{rrm}			26		A

Module Physical Characteristics (Per Position)

Parameter	Symbol	Test condition	Min	Typ	Max	Unit
Backside curvature					100	um
Weight	W			24		g
Case Isolation Voltage	V _{isol}	AC, 50 Hz, 1 min	3000			V
Comparative Tracking Index	CTI			600		
Clearance Distance		Terminal to Terminal		5.0		mm
		Terminal to Heatsink		10		
Creepage Distance		Terminal to Terminal		5.0		
		Terminal to Heatsink		11.5		

NTC Thermistor Characteristics (Per Position)

Parameter	Symbol	Test condition	Min	Typ	Max	Unit
Rated Resistance	R _{NTC}	T _{NTC} = 25°C		5		KΩ
Resistance Tolerance at 25°C	ΔR/R		-5		5	%
Beta Value (T2 = 50°C)	β _{25/50}			3380		K
Beta Value (T2 = 50°C)	β _{25/80}			3428		
Beta Value (T2 = 50°C)	β _{25/100}			3455		
Power Dissipation	P _{Max}			100		mW

Capacitance Characteristics

Parameter	Symbol	Test condition	Min	Typ	Max	Unit
Rated capacitance	Cap	T _{NTC} = 25°C		22		nF
Capacitance Tolerance at 25°C	ΔC/C		-5		5	%

Typical Performance

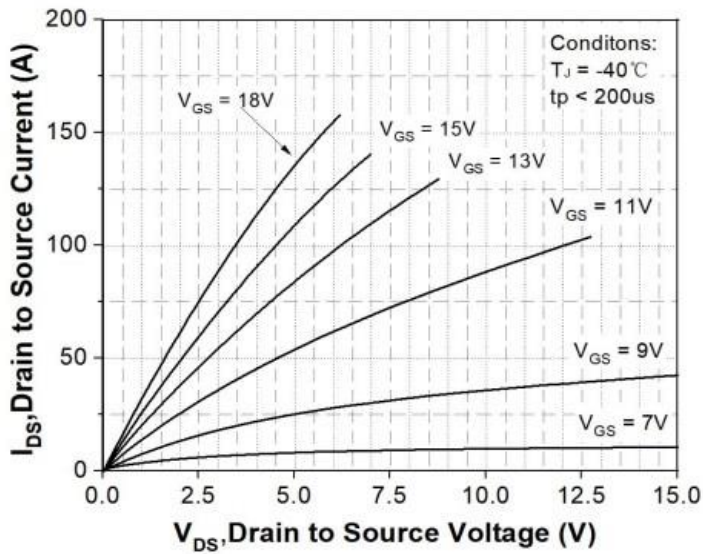


Figure 1. Output characteristic MOSFET

$$I_D = f(V_{DS}), T_{vj} = -40^\circ\text{C}$$

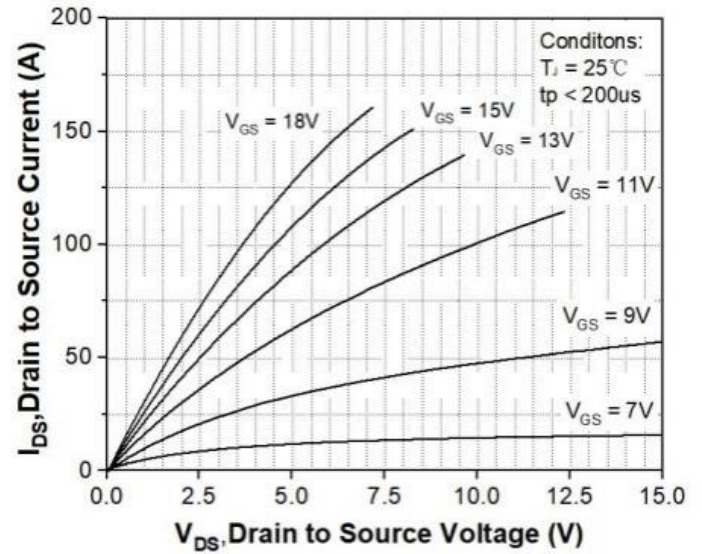


Figure 2. Output characteristic MOSFET

$$I_D = f(V_{DS}), T_v = 25^\circ\text{C}$$

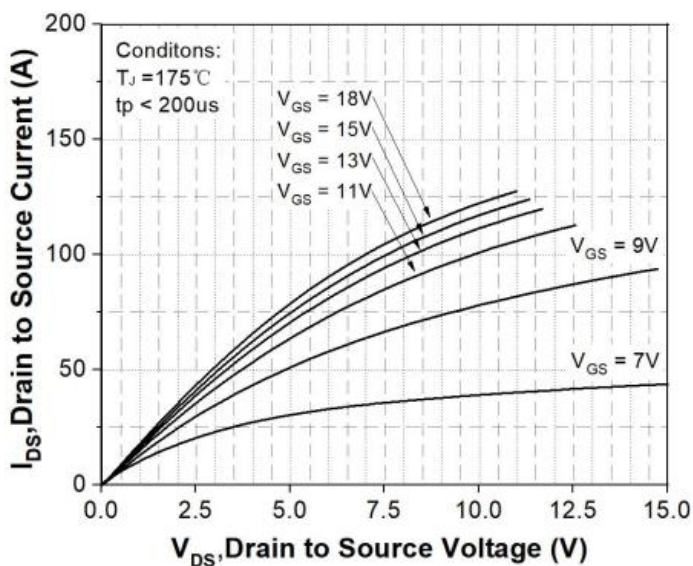


Figure 3. Output characteristic MOSFET

$$I_D = f(V_{DS}), T_{vj} = 175^\circ\text{C}$$

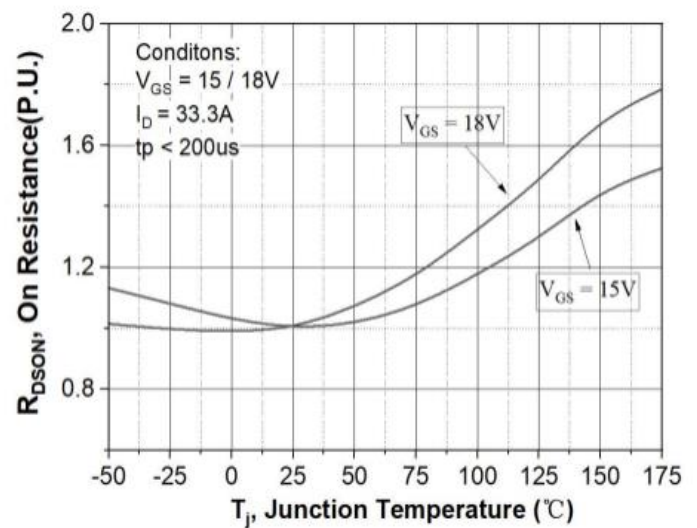


Figure 4. Normalized on-resistance MOSFET

$$R_{ds(on)} = f(T_j), V_{GS} = 15\text{V}/18\text{V}, I_D = 40\text{A}$$

Typical Performance

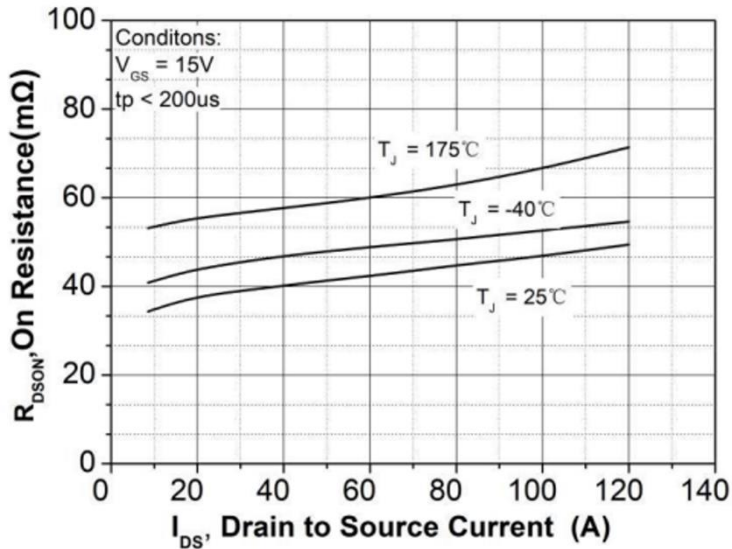


Figure 5. Typical drain-source on-resistances at $V_{GS} = 15V$

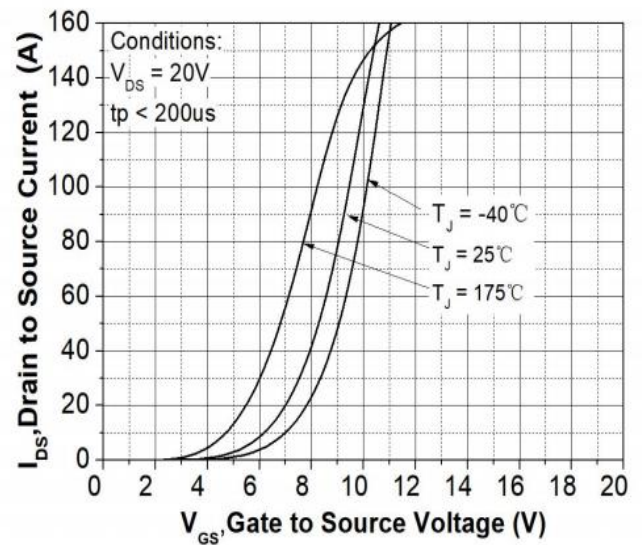


Figure 6. Typical transfer characteristics at $V_{DS} = 20V$

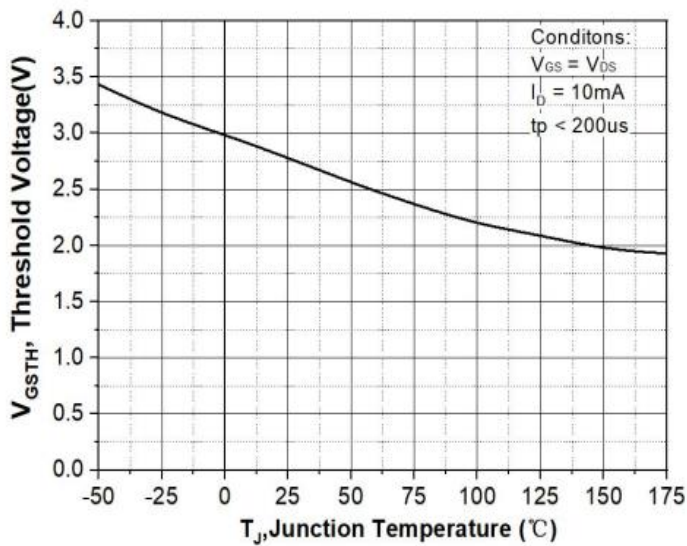


Figure 7. Threshold voltage vs. Junction temperature at $V_{DS} = V_{GS}$ and $I_D = 10mA$

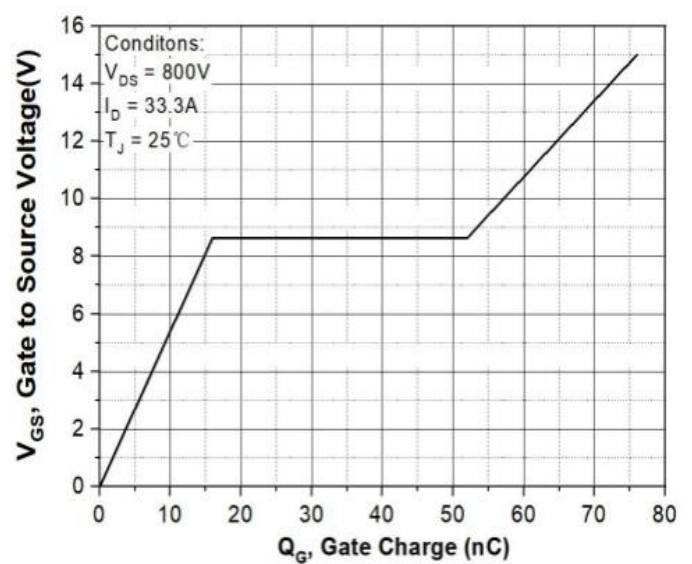


Figure 8. Typical gate charge at $I_D = 33.3A$

Typical Performance

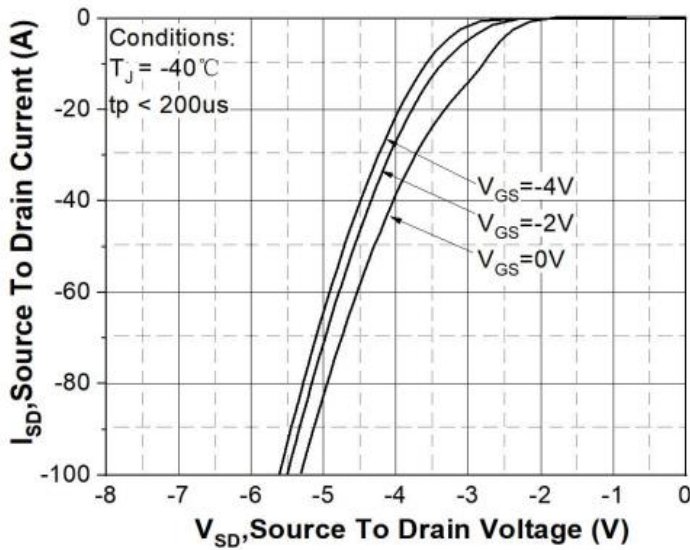


Figure 9. Body diode characteristics at $T_{vj} = -40^\circ\text{C}$

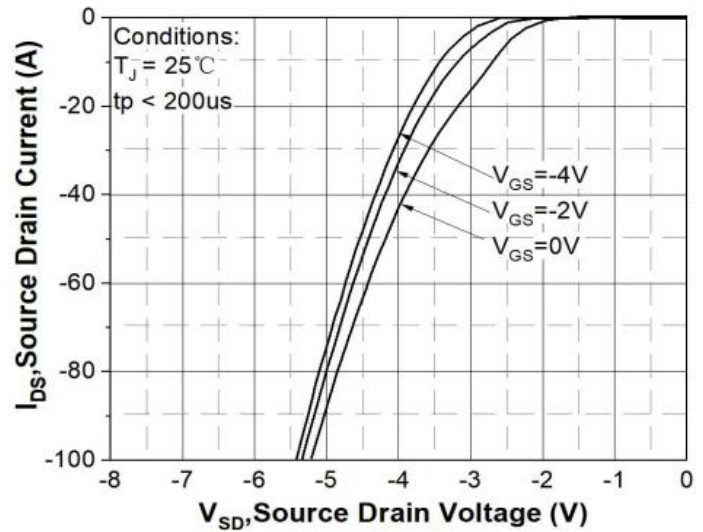


Figure 10. Body diode characteristics at $T_{vj} = 25^\circ\text{C}$

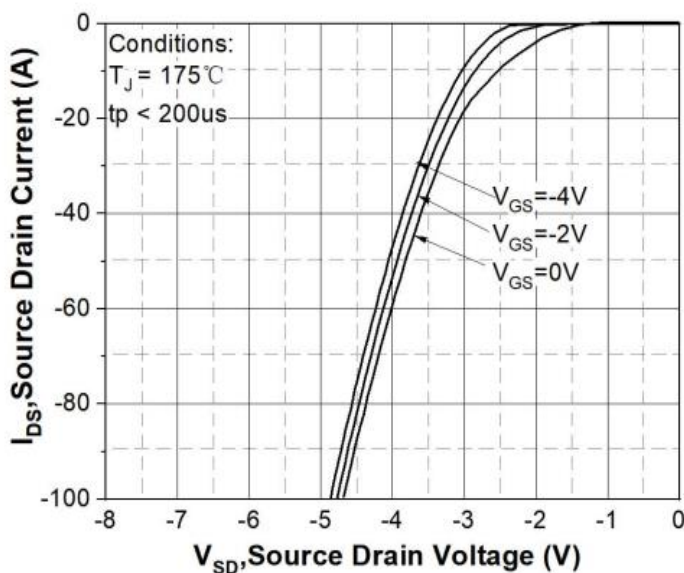


Figure 11. Body diode characteristics at $T_{vj} = 175^\circ\text{C}$

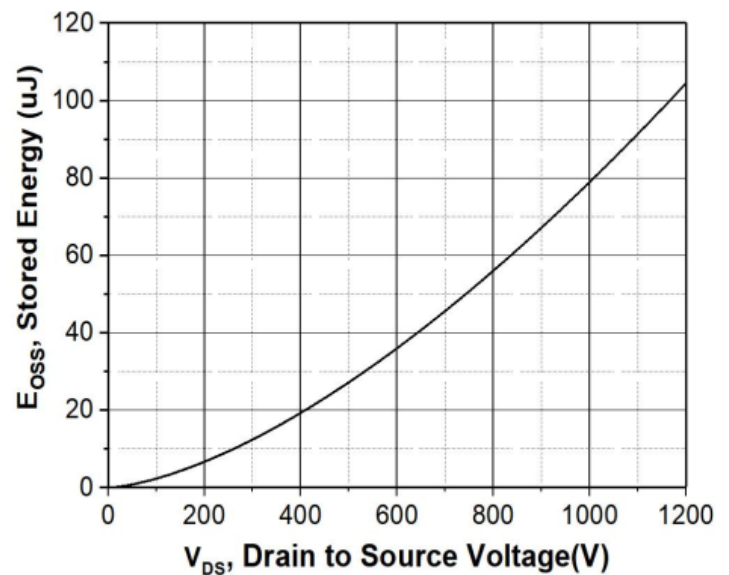


Figure 12. Typical stored energy in C_{oss}

Typical Performance

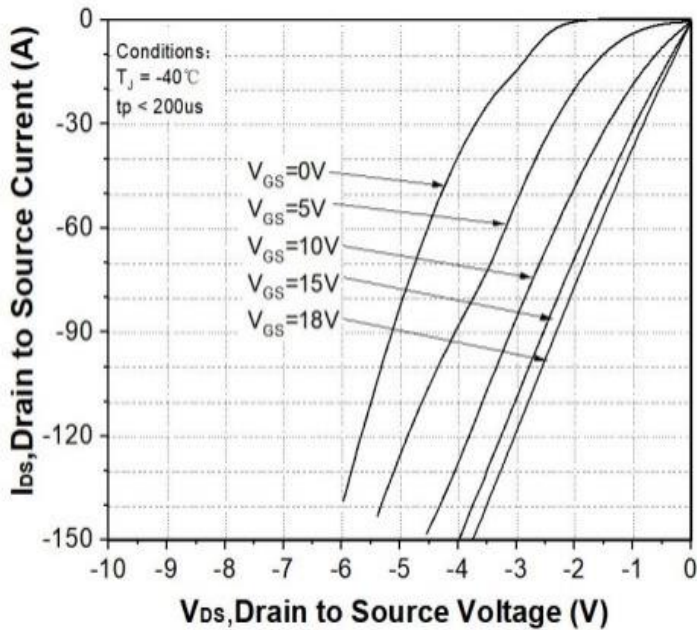


Figure 13. 3rd quadrantat characteristics $T_{vj} = -40^{\circ}\text{C}$

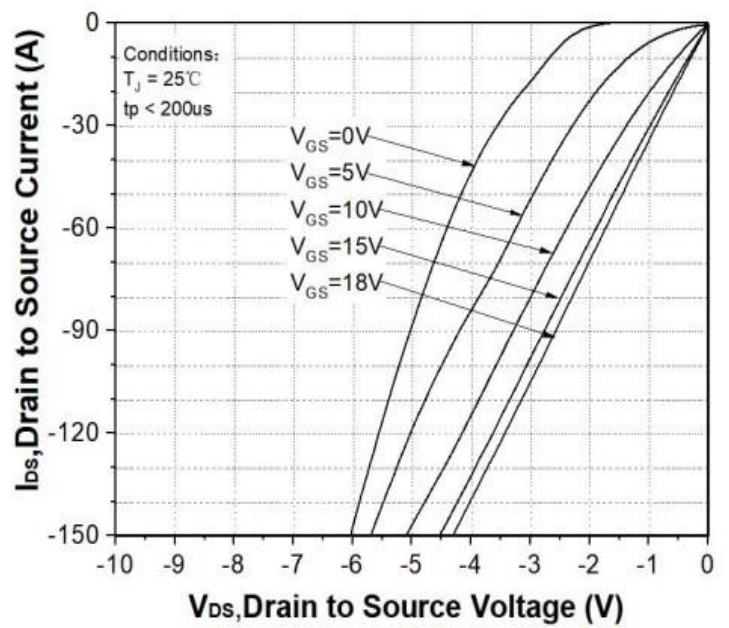


Figure 14. 3rd quadrantat characteristics at $T_{vj} = 25^{\circ}\text{C}$

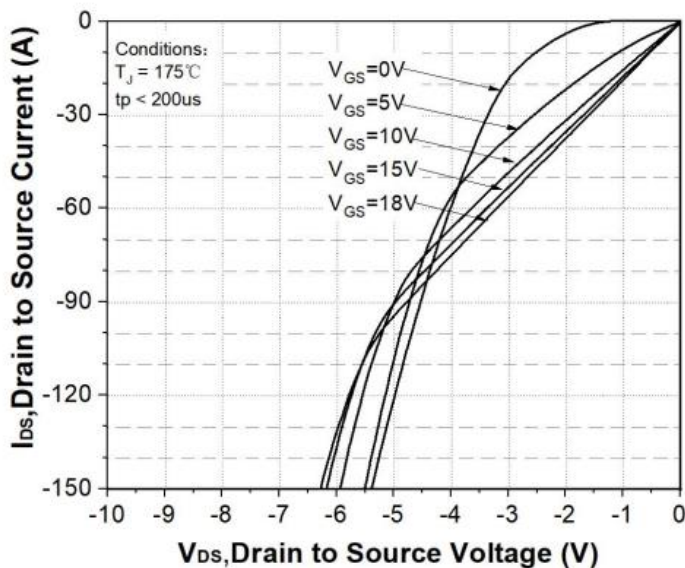


Figure 15. 3rd quadrantat characteristics at $T_{vj} = 175^{\circ}\text{C}$

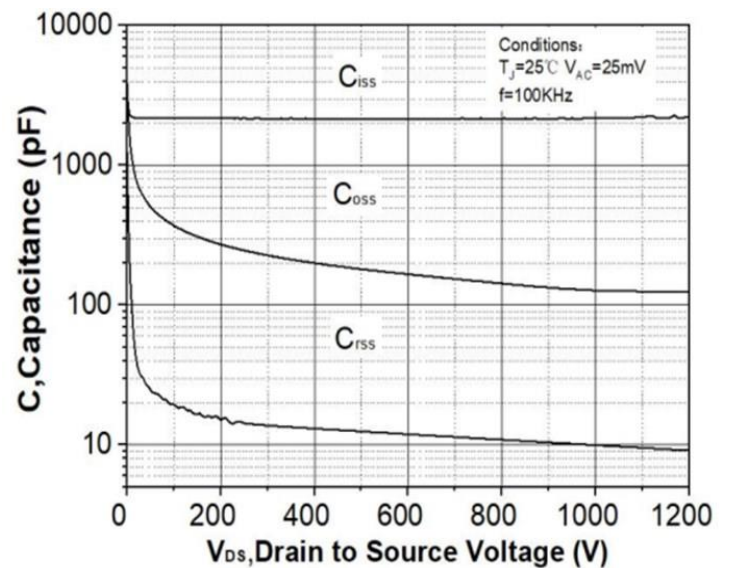
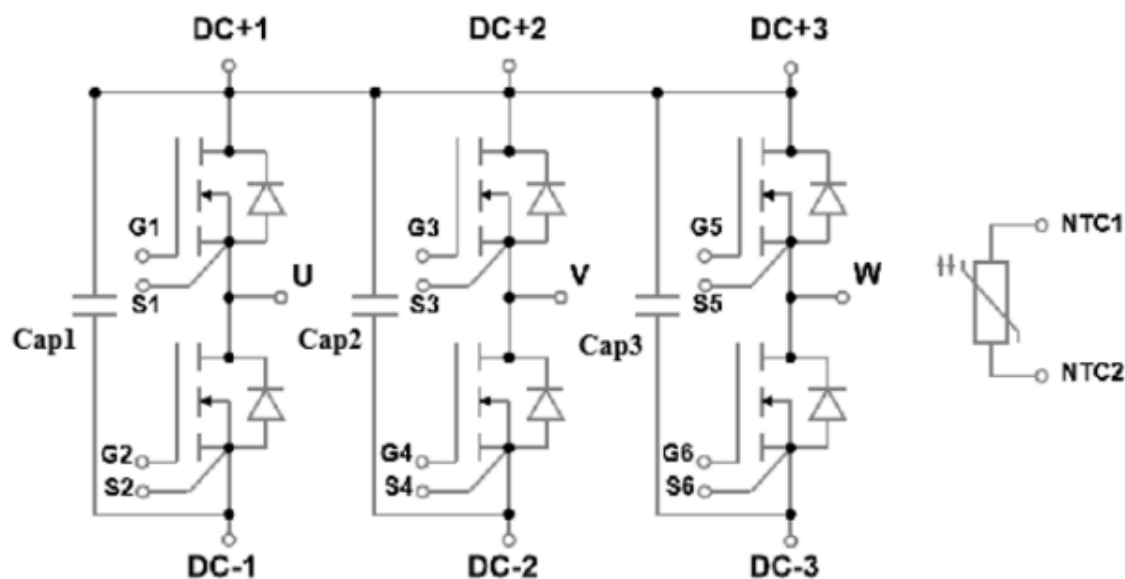


Figure 16. Capacitances at $T_{vj} = 25^{\circ}\text{C}$

Internal Electrical Schematic



Pin Configuration

